

Analysis of a test method for delay faults in NoC interconnects

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A comparison of six languages for system level description of telecom applications

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Delay testing of asynchronous NoC interconnects

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Functional test generation for finite state machines

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A method for crosstalk fault detection in on-chip buses

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Test methods for crosstalk-induced delay and glitch faults in network-on-chip interconnects implementing asynchronous communication protocols

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